

D D D D

G S S S

(2) D

(3) s

Schematic diagram

(1) GO

D D D D

S S S

G

8: B) L*!, @top view

N-Channel Enhancement Mode Power MOSFET

Description

The HM30N04D uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

- V_{DS} =40V,I_D =H0A
- $R_{DS(ON)}$ <13m Ω @ V_{GS}=10V
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

Application

- Load switching
- Hard switched and high frequency circuits
- Uninterruptible power supply

100% UIS TESTED!

100% ΔVds TESTED!

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM30N04D	HM30N04D	ÖØÞÍÝÎĖÌŠ	-	-	-

Absolute Maximum Ratings (Tc=25℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	VDS	40	V
Gate-Source Voltage	Vgs	±20	V
Drain Current-Continuous	Ι _D	H0	А
Drain Current-Continuous(T _c =100 ℃)	I _D (100℃)	Œ	A
Pulsed Drain Current	I _{DM}	F00	A
Maximum Power Dissipation	PD	65	W
Derating factor		0.43	W/°C
Single pulse avalanche energy (Note 5)	E _{AS}	400	mJ
Operating Junction and Storage Temperature Range	T _J ,T _{STG}	-55 To 175	°C





Thermal Characteristic

Thermal Resistance, Junction-to-Case^(Note 2)

°C/W

2.3

R_{ejc}

Electrical Characteristics (Tc=25 $^{\circ}$ C unless otherwise noted)

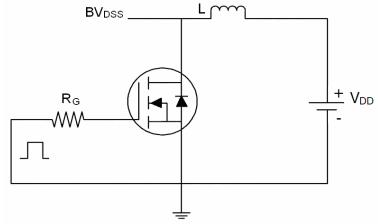
Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics	·					
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250µA	40	45	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =40V,V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)	·					
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} ,I _D =250µA	1.2	1.6	2.5	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =20A	-	7.3	13	mΩ
Forward Transconductance	g fs	V _{DS} =10V,I _D =20A	15	-	-	S
Dynamic Characteristics (Note4)	·					
Input Capacitance	C _{lss}		-	1800	-	PF
Output Capacitance	C _{oss}	$V_{DS}=20V, V_{GS}=0V,$	-	280	-	PF
Reverse Transfer Capacitance	C _{rss}	– F=1.0MHz		190	-	PF
Switching Characteristics (Note 4)	·					
Turn-on Delay Time	t _{d(on)}		-	6.4	-	nS
Turn-on Rise Time	tr	V_{DD} =20V, I_D =2A, R_L =1 Ω	-	17.2	-	nS
Turn-Off Delay Time	t _{d(off)}	V _{GS} =10V,R _G =3Ω	-	29.6	-	nS
Turn-Off Fall Time	t _f		-	16.8	-	nS
Total Gate Charge	Qg)/ _20)// _20 A	-	29		nC
Gate-Source Charge	Q _{gs}	V _{DS} =20V,I _D =20A, V _{GS} =10V	-	4.5		nC
Gate-Drain Charge	Q _{gd}	V _{GS} -10V	-	6.4		nC
Drain-Source Diode Characteristics	·					
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =10A	-		1.2	V
Diode Forward Current (Note 2)	I _S		-	-	30	Α
Reverse Recovery Time	t _{rr}	TJ = 25°C, IF = 20A	-	29	-	nS
Reverse Recovery Charge	Qrr	di/dt = 100A/µs ^(Note3)	-	26	-	nC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD				

Notes:

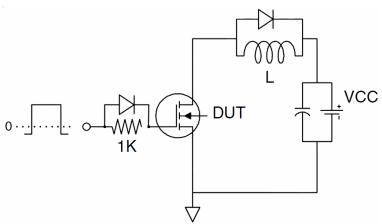
- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board, $t \le 10$ sec.
- **3.** Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2%.
- 4. Guaranteed by design, not subject to production
- **5.** E_{AS} condition : Tj=25 °C, V_{DD} =20V, V_G =10V,L=1mH, Rg=25 Ω ,



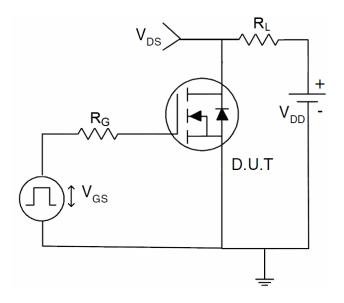
Test circuit 1) E_{AS} Test Circuit



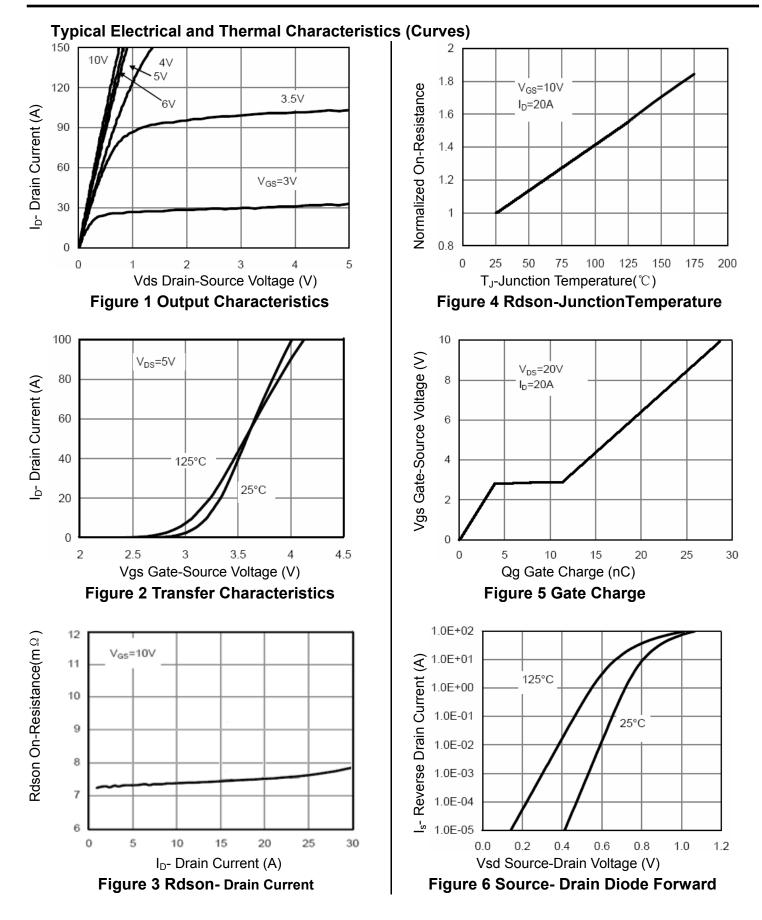
2) Gate Charge Test Circuit



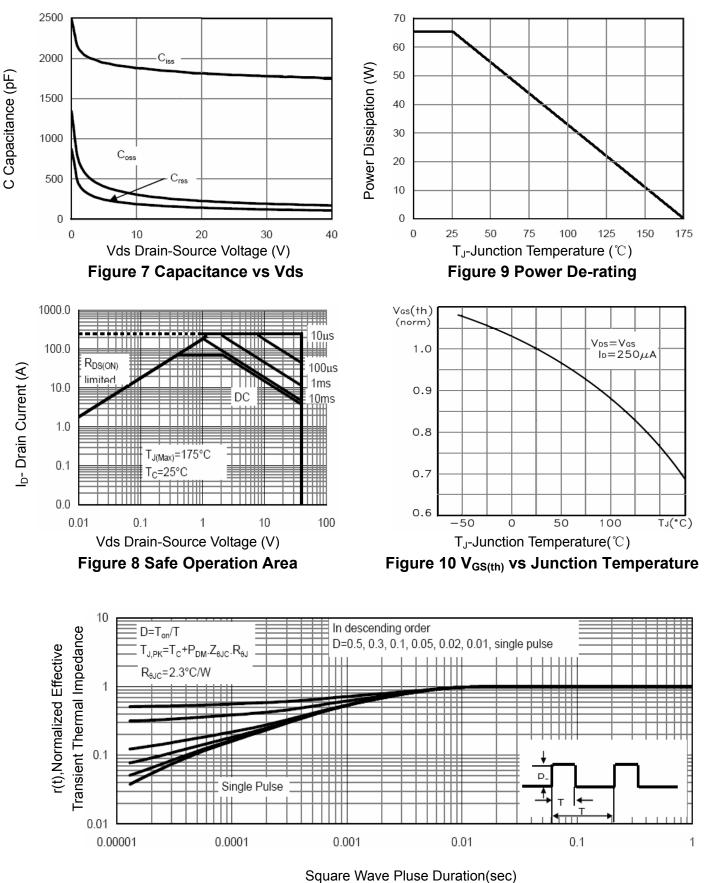
3) Switch Time Test Circuit

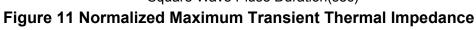






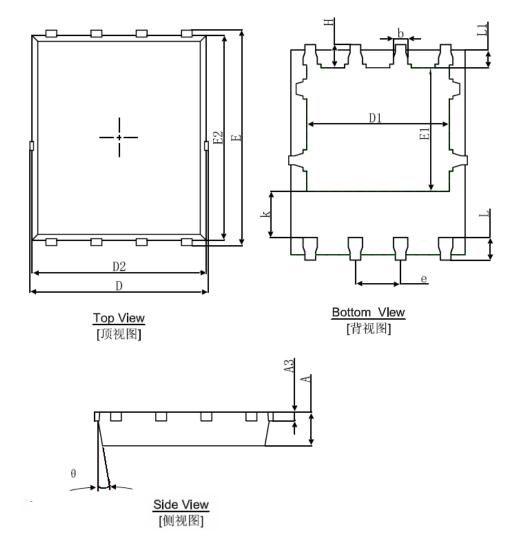








DFN5X6-8L Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches		
	Min.	Max.	Min.	Max.	
А	0.900	1.000	0.035	0.039	
A3	0.254REF.		0.010REF.		
D	4.944	5.096	0.195	0.201	
E	5.974	6.126	0.235	0.241	
D1	3.910	4.110	0.154	0.162	
E1	3.375	3.575	0.133	0.141	
D2	4.824	4.976	0.190	0.196	
E2	5.674	5.826	0.223	0.229	
k	1.190	1.390	0.047	0.055	
b	0.350	0.450	0.014	0.018	
е	1.270TYP.		0.050TYP.		
L	0.559	0.711	0.022	0.028	
L1	0.424	0.576	0.017	0.023	
Н	0.574	0.726	0.023	0.029	
θ	8°	12°	8°	12°	



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